

Notice of References Cited

Application/Control No.

10/754,921

Applicant(s)/Patent Under
Reexamination
WELCH ET AL.

Examiner

DAVID TUROCY

Art Unit

1792

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,140,456	10-2000	Lee et al.	528/196
*	B	US-5,879,808	03-1999	Wary et al.	428/411.1
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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